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2881

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Shing M. Lee

Attorney Docket No.: KLA1P012/P647US

Application No.: 09/695,726

Examiner: Fernandez, K.

Filed: October 23, 2000

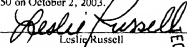
Group: 2881

Title: FILM THICKNESS MEASUREMENT
USING ELECTRON-BEAM INDUCED
X-RAY MICROANALYSIS

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail to: Commissioner for Patents, P.O. Box 1350, Alexandria, VA 22313-1450 on October 2, 2003.

Signed:


Leslie RussellAMENDMENT TRANSMITTAL

Mail Stop Non-Fee Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Transmitted herewith is an Amendment in the above-identified application.

The fee has been calculated as shown below.

	Claims After Amendment		Highest Previously Paid For	Present Extra	Small Entity Rate Fee	Large Entity Rate Fee
Total Claims	22	MINUS	30	00	x 9 =	x 18 = 0.00
Independent Claims	03	MINUS	06	00	x 42 =	x 84 = 0.00
Multiple Dependent Claim Present and Fee Not Previously Paid					\$140.00	\$280.00
Total					\$	\$0.00

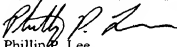


Applicant(s) believe that no (additional) Extension of Time is required; however, if it is determined that such an extension is required, Applicant(s) hereby petition that such an extension be granted and authorize the Commissioner to charge the required fees for an Extension of Time under 37 CFR 1.136 to Deposit Account No. 500388.



Please charge the required fees, or any additional fees required to facilitate filing the enclosed response, to Deposit Account No. 500388 (Order No. KLA1P012).

Respectfully submitted,
BEYER WEAVER & THOMAS, LLP



Phillip P. Lee
Reg. No. 46,866

P.O. Box 778
Berkeley, CA 94704-0778

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Printed Name: Leslie Russell

Signed: 

RESPONSE E

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

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Dear Sir:

In response to the Office Action dated July 8, 2003, a response to which is due on October 8, 2003, please consider the following amendments and remarks:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 7 of this paper.